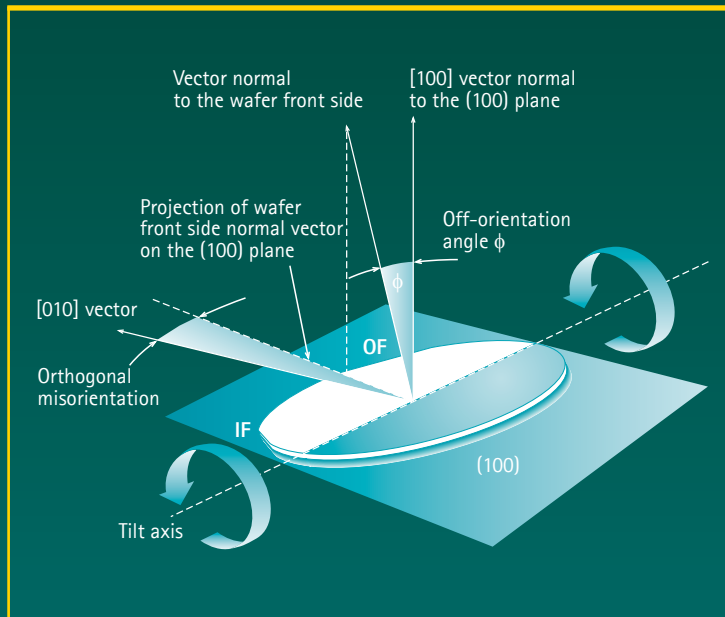




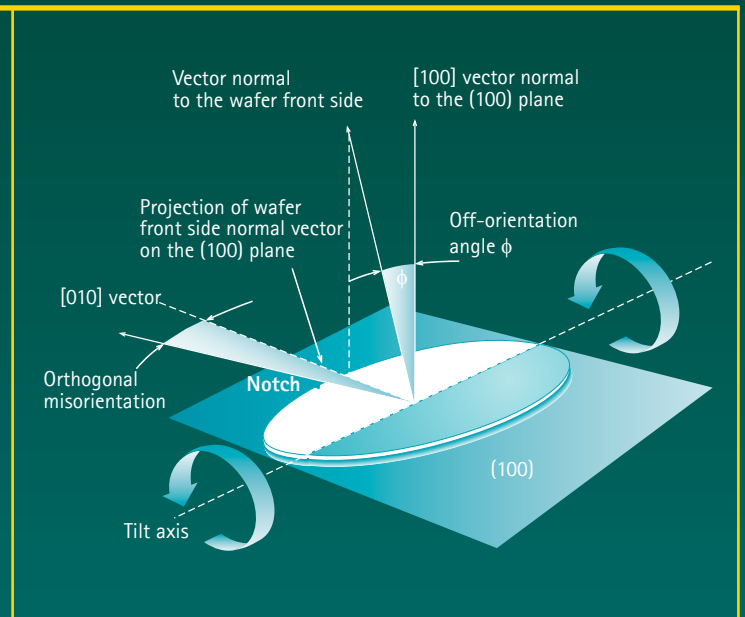
Surface Orientation

Off-orientation by crystallographic directions

Standard off-orientation for V-groove (US) flat option



Standard off-orientation for notch option



Off-orientation by tilt azimuth angle ϵ

As a reference, a line is drawn from the center point of the wafer front surface to the center of the primary flat or the apex of the notch.

The tilt azimuth angle, ϵ , is the angle measured clockwise from the reference line to the direction of off-orientation.

The tilt angle, ϕ , is defined by moving the vector normal on the reference plane towards the wafer surface in the direction defined by the ϵ angle.

